



#3307

Microscopy

STRUCTURAL AND MORPHOLOGICAL ANALYSIS OF
MATERIALS

DESCRIPTION

Optical, electron (SEM, TEM) and atomic force microscopy (AFM) can be used to study the microstructure, morphology, particle size, and defects of materials in micrometric and nanometric scale.

AVAILABLE EQUIPMENT

- Optical Microscope Karl Zeiss, reflection, transmission and polarized light modes with a hot stage (Mettler)
- Scanning Electron Microscope SEM JEOL EVO 40-XVP coupled to an auxiliary Energy Dispersive X-ray Spectroscopy (EDS) detector
- Transmission Electron Microscope (TEM) Jeol 100CX
- Atomic Force Microscope (AFM) Nanoscope (Digital Instruments)

ADVANTAGES

- Besides high resolution images, these analytical techniques can provide valuable information for R&D and the analysis of materials failure.

APPLICATIONS

Nanoparticles | Thin polymeric films and multilayer laminates |
Coatings | Composites and nanocomposites | Voids, cracks and
defects | Crystalline structure

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